S	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/791,186	LEE ET AL.	
Examiner	Art Unit	

Matthew G. Kayrish

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	SEAR	CHED	
Class	Subclass	Date	Examiner
360	126	5/18/2006	мк

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		 	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPG-PUB, USPAT, USOCR, EPO, JPO, IBD_TDB, DERWENT) (See Attached Search History)	^C 5/18/2006	мк